

# Optimize your radiographic inspection

### **Background**

Specifying the primary parameters for a radiographic inspection to ensure an interpretable image is often difficult. Before taking X-rays, it is necessary to:

- Select the appropriate **X-ray** source.
- Determine the best **position and orientation** of the source with respect to the test specimen.
- Specify the correct **exposure time** to ensure a usable image.

An incorrect setting for any of these parameters almost always requires additional shots.

### **Benefits**

Using CIVA for radiographic inspections, you can a priori identify the **key parameters** and specify their values for each source.

For example, it is possible to predict **the optical density** of the image obtained on the radiographic film, and thus defect visibility.

CIVA allows you to reduce the number of experimental trials, thereby reducing operator exposure to radiation.







## Optimize your radiographic inspection

### Case study

### Select the most suitable source for radiographic inspection

#### ■ THE PROBLEM

The **thickness** and **density of the test specimen** are the primary considerations in choosing the X-ray source that will be used for the inspection.

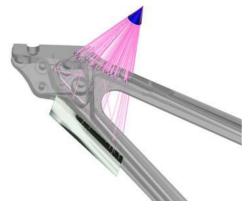
Use of a source that is **too powerful** results in an unusable saturated image.

In contrast, a source with insufficient energy prevents the photons from traversing the specimen.

#### ■ CIVA'S CONTRIBUTION

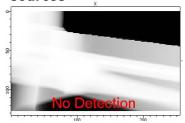
CIVA allows you to optimize your RT inspection strategy and protocols:

- **Test X-ray sources** to determine which yields the best result.
- Determine the effect of radiation on the inspection result.
- Analyze detection sensitivity.
- Choose the source and configuration that provides the optimal result.

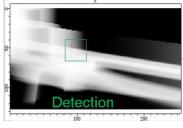


CIVA estimation of photon paths through the test specimen from the source to the detector.

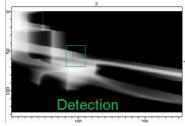
### Results obtained for three different RT sources



Case 1 - Source 140kV / 5mA
The defect is not detected.



Case 2 - 200kV Source / 5mA The defect is detected, but contrast is poor.



Case 3 - 300kV Source / 5mA
The defect is easily detected.

#### www.extende.com

